Abstracts

2D Electro-Optic Probing Combined with Field Theory Based Multimode Wave Amplitude Extraction: A New Approach to On-Wafer Measurement

G. David, W. Schroeder, D. Jager and I. Wolff. "2D Electro-Optic Probing Combined with Field Theory Based Multimode Wave Amplitude Extraction: A New Approach to On-Wafer Measurement." 1995 MTT-S International Microwave Symposium Digest 95.3 (1995 Vol. III [MWSYM]): 1049-1052.

A novel approach to on-wafer measurement is proposed, which combines the direct electro-optic probing technique with a field theory based extraction technique for the modal voltages of all relevant modes at arbitrary internal ports of a (III-V) MMIC. The approach can be extended to obtain the complex modal amplitudes of forward and backward propagating waves on interconnecting transmission lines. This makes it a unique method for measurement of mode conversion in N-port components and their multimode s-parameter characterization.

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